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retention time	Semiconductor nonvolatile memory with wide memory window and long data		Non-volatile semiconductor memory	method of manufa	Semiconductor device having thin electrode layer adjacent gate	Semiconductor nonvolatile memory cell	gate	Nonvolatile memory cell with P-N junction formed in polysilicon floating	and_method_of_fabrication	Virtual ground flash cell with asymmetrically placed source and drain	protruding conductive	Non-volatile semiconductor memory device having a floating gate with	manufacturing_method	Floating gate non-volatile memory cell with low erasing voltage and	providing	Flash EPROM cell with reduced short channel effect and method for	Title
	257/324	257/318		25//31/		257/316		257/316		257/315		257/315		257/314	C	757737	Current OR
/2	257/406 ; 257/411 ; 257/637 ; 257/640	; 257/315 ; 257/316 ; 257/317 ; 257/322	257/262 ; 257/264 ; 257/314	; 257/321	257/315	257/324 ; 257/325 ; 257/411	; 365/185.1 ; 438/264	257/315 ; 257/317 ; 257/318 ; 365/185.01		257/321	; 438/304	257/288 ; 257/387 ; 438/257		257/316 ; 257/324		257/315 ; 257/404	Current XRef
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10	US 6236085 B1	20010522	N 5	Semiconductor memory device having high-concentration region around 25 electric-field moderating layer in substrate	57/345	257/315 ; 257/316 ; 257/318 ; 257/319 ; 257/320 ; 257/321 ; 257/322 ; 257/326 ; 257/344 ; 257/408 ; 257/408 ; 257/900	Kawaguchi, Tsutomu , et al.
11	US 6137718 A	20001024	6	non-volatile 3	65/185.03	257/324 ; 365/185.28	Reisinger, Hans
12	US 4996571 A	19910226	15	tor memory 3	65/185.19	257/321 ; 365/185.06 ; 365/185.09 ; 365/185.23 ; 365/185.3 ; 365/218	Kume, Hitoshi , et al.
13	US 5432749 A	19950711	7	Non-volatile memory cell having hole confinement layer for reducing 36	65/218	257/315 ; 365/185.17	Sethi, Rakesh B.
14	US 5904518 A	19990518	18	(b)	38/201	438/258	Komori, Kazuhiro , et al.
15	us 6238967 B1	20010529	14	Method of forming embedded DRAM 43	38/244	438/243	Shiho, Yasuhito , et al.
16	US 5814543 A	19980929	ω 5	Method of manufacturing a semicondutor integrated circuit device having	138/264	438/265 ; 438/592	Nishimoto, Toshiaki , et al.

	Туре	Hits	Search Text	DBs	Time Stamp
1	IS&R	10	(("4577215") or ("5482879") or ("5879992") or ("6229176") or ("5016068") or ("5295107") or ("6046086") or ("4442447") or ("4513397") or ("4592130")).PN.	USPAT: US-PGPUB	2001/09/17 08:33
2	IS&R	40	(("4618876") or ("4903097") or ("5526307") or ("5760435") or ("6069381") or ("6207989") or ("6239465") or ("4417264") or ("4558339") or ("4590665") or ("4802137") or ("5212541") or ("5216268") or ("5216269") or ("5289026") or ("5292681") or ("5432109") or ("5447877") or ("5457061") or ("5595920") or ("5605853") or ("5612237") or ("5625213") or ("5702965") or ("5801993") or ("5814543") or ("5851880") or ("5877525") or ("5858840") or ("5877525") or ("5940705") or ("5946240") or ("5950087") or ("6037226") or ("6034892") or ("6037226") or ("6180977") or ("6188102")).PN.	USPAT: US-PGPUB	2001/09/17 08:33
3	IS&R	54	("438/288").CCLS.	USPAT: US-PGPUB	2001/09/17 09:30
4	IS&R	652	("257/315").CCLS.	USPAT; US-PGPUB	2001/09/17 09:56
5	IS&R	309	("257/324").CCLS.	USPAT; US-PGPUB	2001/09/17 09:56
6	BRS	267	(("257/324").CCLS.) not (("257/315").CCLS.)	USPAT: US-PGPUB	2001/09/17 09:57
7	BRS	342	asymmetric same source same drain	USPAT; US-PGPUB	2001/09/17 11:13
8	BRS	240	asymmetric with source with drain	USPAT: US-PGPUB	2001/09/17 11:13
9	BRS	159	(asymmetric with source with drain) and memory	USPAT; US-PGPUB	2001/09/17 11:14